

**JAYPEE UNIVERSITY OF INFORMATION TECHNOLOGY, WAKNAGHAT**  
**TEST-2 EXAMINATION- APRIL -2018**  
**B.Tech VI Semester**

COURSE CODE: 10B11EC612

MAX. MARKS: 25

COURSE NAME: VLSI TECHNOLOGY AND APPLICATIONS

COURSE CREDITS: 04

MAX. TIME: 1 HRS 30 MIN

*Note: All questions are compulsory. Carrying of mobile phone during examinations will be treated as case of unfair means.*

1. (CO1, CO4) [1 × 5 = 5]
- How noise sensitivity is different from noise immunity?
  - Draw and explain the high frequency model of a MOSFET.
  - A slow circuit dissipates less power than a fast circuit. Justify.
  - Threshold voltage of a MOSFET is -1.35V. Which all MOSFET's satisfy this specification? Draw symbols.
  - A depletion type  $n$ -channel MOSFET is biased in its linear region for use as a voltage controlled resistor. Assume  $V_{th} = 0.5V$ ,  $V_{GS} = 2V$ ,  $V_{DS} = 5V$ ,  $W/L = 100$ ,  $C_{ox} = 10^{-8} F/cm^2$  and  $\mu_n = 800 cm^2/V\text{-sec}$ . The value of the resistance of the voltage controlled resistor (in  $m\Omega$ ) is \_\_\_\_\_.
2. (CO1, CO3) [3 + 3 = 6]
- Consider  $n$ -MOS transistor with source and body connected together. Calculate the threshold voltage (in volts) of the transistor assuming that the electron mobility is dependent of  $V_{GS}$  and  $V_{DS}$ . Given :  $g_m = 0.5 \mu A/V$  for  $V_{DS} = 50mV$  and  $V_{GS} = 2V$ .  
 $g_d = 8 \mu A/V$  for  $V_{GS} = 2V$  and  $V_{DS} = 0V$ .
- $$\text{where } g_m = \frac{\partial I_D}{\partial V_{GS}} \text{ and } g_d = \frac{\partial I_D}{\partial V_{DS}}$$
- Calculate the parasitic drain capacitance for  $n$ -MOS transistor operating at  $W = 5 \mu m$ ,  $L = 0.5 \mu m$ ,  $Y = 3 \mu m$ ,  $\phi_0 = 0.7V$ ,  $\phi_{0sw} = 0.9V$ ,  $C_{sb0} = 0.86 fF/\mu m^2$ ,  $C_{db0} = 0.24 fF/\mu m^2$ ,  $C_{sbsw} = 0.24 fF/\mu m$ ,  $C_{dbsw} = 0.24 fF/\mu m$ ,  $\eta = 0.36$ ,  $m_{sw} = 0.4$  and reverse bias voltage  $3V$ .
3. (CO3) [6]
- Design Linear RC model of an  $n$ -channel MOS transistor having parameters : substrate doping density =  $10^{16}/cm^3$ , polysilicon gate doping density =  $2 \times 10^{20}/cm^3$ ,  $N_{A(\text{chanstop})} = 10^{19}/cm^3$ , gate oxide thickness =  $50nm$ , oxide interface fixed charge density =  $4 \times 10^{10}/cm^2$ , abrupt junction depth =  $0.4 \mu m$ , length of drain =  $9 \mu m$ , width =  $4 \mu m$ , length of channel =  $1.5 \mu m$ , drain to bulk voltage =  $1.5V$ , gate to source voltage =  $1.5V$ , drain to source voltage =  $1.5V$ , threshold voltage =  $0.8V$ , electron mobility =  $650 cm^2/V\text{-s}$ . Assume diffusion capacitance.
4. (CO4) [2 × 4 = 8]
- Design a resistive load inverter with  $R = 1 k\Omega$ , such that  $V_{OL} = 1V$ . The enhancement type  $n$ MOS driver transistor has the following parameters:  $\mu_n C_{ox} = 22 \mu A/V^2$ ,  $V_{TO} = 1V$ ,  $V_{DD} = 4.0V$ . Determine the required aspect ratio. Determine input low voltage parameter.
  - Draw the VTC curve for resistive load  $n$ -MOS inverter. Determine the  $V_{OH}$  and  $V_{OL}$  when biased at  $V_{DD} = 2.5V$ ,  $k' = 1 \mu A/V^2$ ,  $V_{thD} = 0.5V$ ,  $(W/L)_D = 10$ ,  $R = 2K\Omega$ .